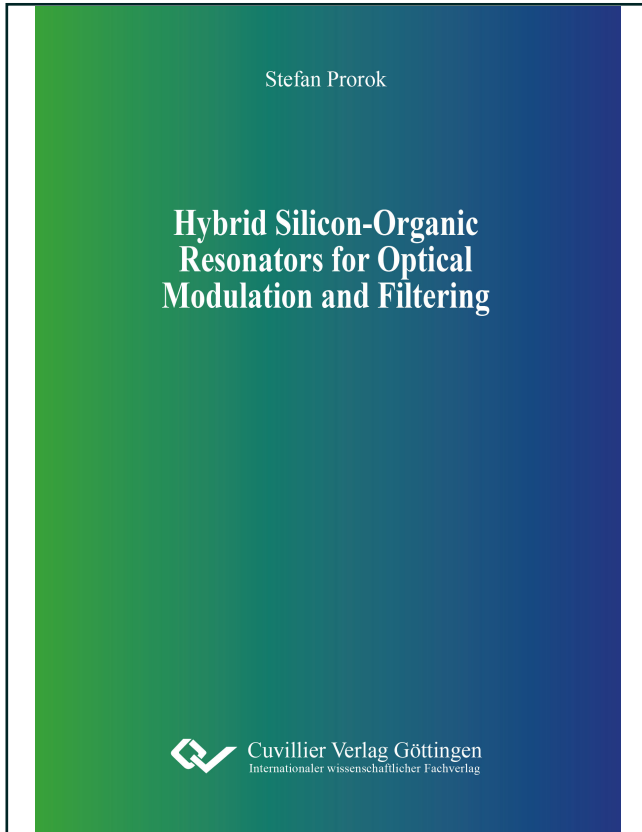




Stefan Prorok (Autor)
**Hybrid Silicon-Organic Resonators for Optical
Modulation and Filtering**



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